

MOSFET – Power, Single N-Channel, μ8FL 30 V, 5.9 mΩ, 55 A NVTFS4C08N

Features

- Low R_{DS(on)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- NVTFS4C08NWF Wettable Flanks Product
- NVT Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

MAXIMUM RATINGS (T_J = 25°C unless otherwise stated)

Param	Symbol	Value	Unit		
Drain-to-Source Voltage			V _{DSS}	30	V
Gate-to-Source Voltage			V_{GS}	±20	V
Continuous Drain		T _A = 25°C	I _D	17	Α
Current R _{θJA} (Notes 1, 2, 4)		T _A = 100°C		12	
Power Dissipation R _{θJA}		T _A = 25°C	P_{D}	3.1	W
(Note 1, 2, 4)	Steady	T _A = 100°C		1.6	
Continuous Drain Current R _{θJC} (Note 1,	State	T _A = 25°C	I _D	55	
3, 4)		T _A = 100°C		39	Α
Power Dissipation		T _A = 25°C	P_{D}	31	W
R _{θJC} (Note 1, 3, 4)		T _A = 100°C		15	
Pulsed Drain Current	T _A = 25°	C, t _p = 10 μs	I _{DM}	253	Α
Operating Junction and Storage Temperature			T _J , T _{stg}	-55 to +175	°C
Source Current (Body Diode)			I _S	28	Α
Single Pulse Drain–to–Source Avalanche Energy ($T_J = 25^{\circ}C$, $I_L = 20 A_{pk}$, $L = 0.1 mH$)			E _{AS}	20	mJ
Lead Temperature for So (1/8" from case for 10 s)	ldering Pur	poses	TL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

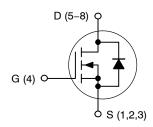
THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State (Drain) (Notes 1 and 4)	$R_{\theta JC}$	4.9	°C/W
Junction-to-Ambient - Steady State (Notes 1 and 2)	$R_{\theta JA}$	48	O/ VV

- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Surface-mounted on FR4 board using a 650 mm² 2 oz. Cu pad.
- Assumes heat-sink sufficiently large to maintain constant case temperature independent of device power.
- 4. Continuous DC current rating. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.

V _{(BR)DSS}	R _{DS(on)} MAX	I _D MAX	
30 V	5.9 mΩ @ 10 V	55 A	
	9.0 mΩ @ 4.5 V	33 A	

N-Channel MOSFET

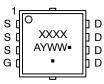


MARKING DIAGRAM WDFN8 1



CASE 511AB

WDFNW8 CASE 515AN



4C08 = Specific Device Code for

NVMTS4C08N

08WF = Specific Device Code of

NVTFS4C08NWF

A = Assembly Location

Y = Year
WW = Work Week
= Pb-Free Package

(Note: Microdot may be in either location)

ORDERING INFORMATION

See detailed ordering and shipping information on page 5 of this data sheet.

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS	1						1
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V}, I_D =$	250 μΑ	30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} / T _J				13.8		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	$V_{GS} = 0 V$	T _J = 25°C			1.0	
		V _{DS} = 24 V	T _J = 125°C			10	μΑ
Gate-to-Source Leakage Current	I _{GSS}	$V_{DS} = 0 V, V_{GS}$	= ±20 V			±100	nA
ON CHARACTERISTICS (Note 5)							
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D = I_{DS}$	= 250 μΑ	1.3		2.2	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				5.0		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 30 A		4.7	5.9	0
		V _{GS} = 4.5 V	I _D = 18 A		7.2	9.0	mΩ
Forward Transconductance	9 _{FS}	V _{DS} = 1.5 V, I _E	₎ = 15 A		42		S
Gate Resistance	R_{G}	T _A = 25°	С		1.0		Ω
CHARGES AND CAPACITANCES							
Input Capacitance	C _{ISS}				1113		
Output Capacitance	Coss	V _{GS} = 0 V, f = 1 MHz, V _{DS} = 15 V			702		pF
Reverse Transfer Capacitance	C _{RSS}				39		
Capacitance Ratio	C _{RSS} /C _{ISS}	V _{GS} = 0 V, V _{DS} = 15 V, f = 1 MHz			0.035		
Total Gate Charge	Q _{G(TOT)}				8.4		
Threshold Gate Charge	Q _{G(TH)}	V _{GS} = 4.5 V, V _{DS} = 15 V; I _D = 30 A			1.8		nC
Gate-to-Source Charge	Q_{GS}				3.5		
Gate-to-Drain Charge	Q_{GD}				3.3		
Gate Plateau Voltage	V_{GP}				3.4		V
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 10 V, V _{DS} = 15 V; I _D = 30 A			18.2		nC
SWITCHING CHARACTERISTICS (Note 6)	, ,	•					
Turn-On Delay Time	t _{d(ON)}				9.0		
Rise Time	t _r	$V_{GS} = 4.5 \text{ V}, V_{DS}$	e = 15 V.		33		
Turn-Off Delay Time	t _{d(OFF)}	I _D = 15 A, R _G	= 3.0 Ω		15		ns
Fall Time	t _f				4.0		
Turn-On Delay Time	t _{d(ON)}				7.0		
Rise Time	t _r	Vcc = 10 V Vc	s = 15 V		26		
Turn-Off Delay Time	t _{d(OFF)}	V_{GS} = 10 V, V_{DS} = 15 V, I_{D} = 15 A, R_{G} = 3.0 Ω			19		ns
Fall Time	t _f				3.0		
DRAIN-SOURCE DIODE CHARACTERISTIC	1	1					
Forward Diode Voltage	V_{SD}	V _{GS} = 0 V,	T _J = 25°C		0.79	1.1	
		I _S = 10 A	T _J = 125°C		0.66		V
Reverse Recovery Time	t _{RR}		<u> </u>		28.3		
Charge Time	t _a	Voo - 0 V dis/d+ -	- 100 A/us		14.5		ns
Discharge Time	t _b	$V_{GS} = 0 \text{ V, dIS/dt} = 100 \text{ A/}\mu\text{s},$ $I_S = 30 \text{ A}$			13.8		1
Reverse Recovery Charge	Q _{RR}				15.3		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

5. Pulse Test: pulse width $\leq 300~\mu s$, duty cycle $\leq 2\%$.

6. Switching characteristics are independent of operating junction temperatures.

TYPICAL CHARACTERISTICS

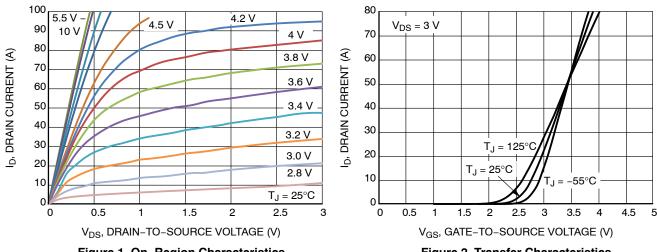


Figure 1. On-Region Characteristics

Figure 2. Transfer Characteristics

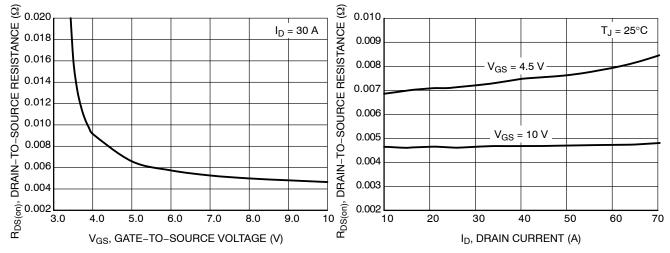


Figure 3. On-Resistance vs. V_{GS}

Figure 4. On-Resistance vs. Drain Current and **Gate Voltage**

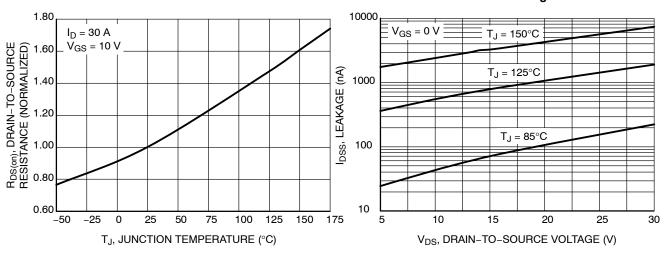


Figure 5. On-Resistance Variation with **Temperature**

Figure 6. Drain-to-Source Leakage Current vs. Voltage

TYPICAL CHARACTERISTICS

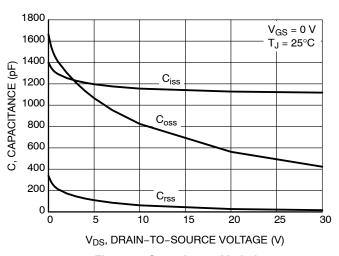


Figure 7. Capacitance Variation

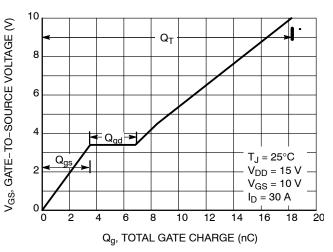


Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

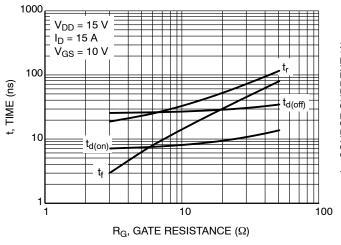


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

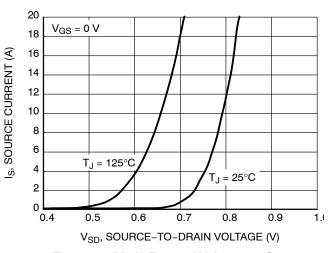


Figure 10. Diode Forward Voltage vs. Current

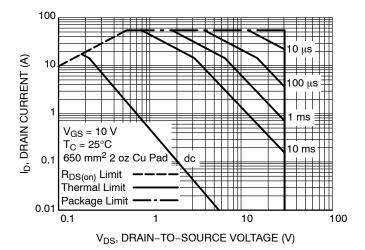


Figure 11. Maximum Rated Forward Biased Safe Operating Area

TYPICAL CHARACTERISTICS

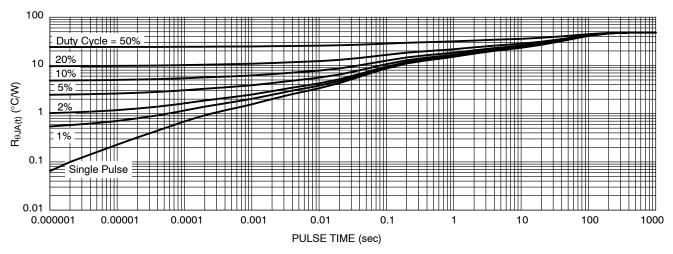


Figure 12. Thermal Response

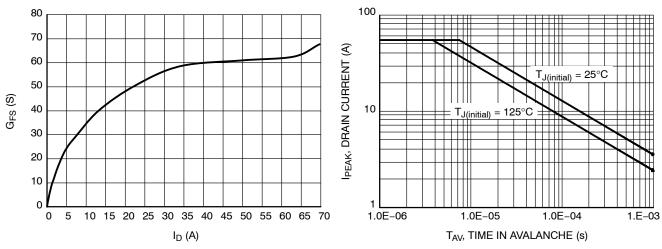


Figure 13. G_{FS} vs. I_D

Figure 14. Avalanche Characteristics

ORDERING INFORMATION

Device	Package	Shipping [†]
NVTFS4C08NTAG	WDFN8 (Pb-Free)	1500 / Tape & Reel
NVTFS4C08NWFTAG	WDFNW8 (Pb-Free)	1500 / Tape & Reel
NVTFS4C08NTWG	WDFN8 (Pb-Free)	5000 / Tape & Reel
NVTFS4C08NWFTWG	WDFNW8 (Pb-Free)	5000 / Tape & Reel

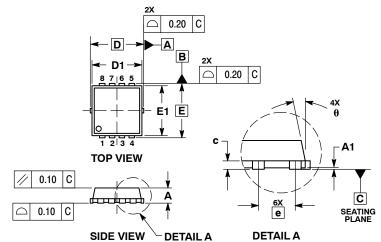
[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.





WDFN8 3.3x3.3, 0.65P CASE 511AB ISSUE D

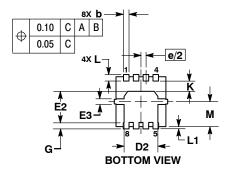
DATE 23 APR 2012



NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
 CONTROLLING DIMENSION: MILLIMETERS.
 DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH
 PROTRUSIONS OR GATE BURRS.

	MILLIMETERS				INCHES	
DIM	MIN	NOM	MAX	MIN	NOM	MAX
Α	0.70	0.75	0.80	0.028	0.030	0.031
A1	0.00		0.05	0.000		0.002
b	0.23	0.30	0.40	0.009	0.012	0.016
С	0.15	0.20	0.25	0.006	0.008	0.010
D		3.30 BSC		0	.130 BSC)
D1	2.95	3.05	3.15	0.116	0.120	0.124
D2	1.98	2.11	2.24	0.078	0.083	0.088
E		3.30 BSC		0	.130 BSC)
E1	2.95	3.05	3.15	0.116	0.120	0.124
E2	1.47	1.60	1.73	0.058	0.063	0.068
E3	0.23	0.30	0.40	0.009	0.012	0.016
е	0.65 BSC			(0.026 BS0	2
G	0.30	0.41	0.51	0.012	0.016	0.020
K	0.65	0.80	0.95	0.026	0.032	0.037
L	0.30	0.43	0.56	0.012	0.017	0.022
L1	0.06	0.13	0.20	0.002	0.005	0.008
М	1.40	1.50	1.60	0.055	0.059	0.063
θ	0 °		12 °	0 °		12 °

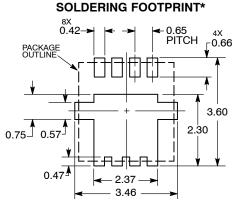


GENERIC MARKING DIAGRAM*



XXXXX = Specific Device Code = Assembly Location

= Year WW = Work Week = Pb-Free Package



DIMENSION: MILLIMETERS

*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

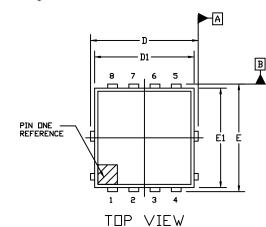
DOCUMENT NUMBER:	98AON30561E	Electronic versions are uncontrolled except when accessed directly from the Document Report Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red.		
DESCRIPTION:	WDFN8 3.3X3.3, 0.65P		PAGE 1 OF 1	

onsemi and ONSEMI are trademarks of Semiconductor Components Industries, LLC dba onsemi or its subsidiaries in the United States and/or other countries. onsemi reserves the right to make changes without further notice to any products herein. onsemi makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does **onsemi** assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. **onsemi** does not convey any license under its patent rights nor the rights of others.

^{*}This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "■", may or may not be present. Some products may not follow the Generic Marking.

WDFNW8 3.3x3.3, 0.65P (Full-Cut μ8FL WF) CASE 515AN ISSUE O

DATE 25 AUG 2020

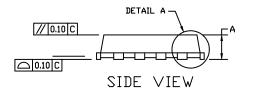


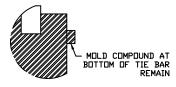


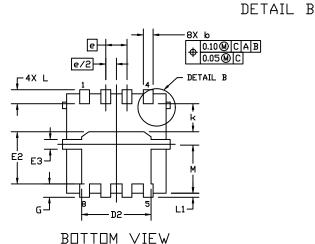
- 1. DIMENSIONING AND TOLERANCING PERASME Y14.5M, 2009.
- 2. CONTROLLING DIMENSION: MILLIMETERS
- DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BURRS.

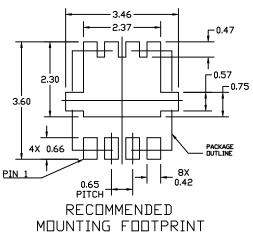
<u> </u>			ATED (AREA
A1 I	DETAIL	Т А	C SEATIN PLANE	IG

	MILLIMETERS				
DIM	MIN.	NDM.	MAX.		
Α	0.70	0.75	0.80		
A1	0.00		0.05		
b	0.23	0.30	0.40		
c	0.15	0.20	0.25		
D	3.05	3.30	3.55		
D1	2.95	3.05	3.15		
D2	1.98	2.11	2.24		
Ε	3.05	3.30	3.55		
E1	2.95	3.05	3.15		
E2	1.47	1.60	1.73		
E3	0.23	0.30	0.40		
e		0.65 BSC			
G	0.30	0.41	0.51		
K	0.65	0.80	0.95		
L	0.30	0.43	0.59		
L1	0.06	0.13	0.20		
М	1.40	1.50	1.60		









* For additional information on our Pb-Free strategy and soldering details, please download the DN Semiconductor Soldering and Mounting Techniques Reference Manual, SDLDERRM/D.

GENERIC MARKING DIAGRAM*

XXXX AYWW• XXXX = Specific Device Code

A = Assembly Location

Y = Year

WW = Work Week

= Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.

(Note: Microdot may be in either location)

DOCUMENT NUMBER:	98AON24556H	Electronic versions are uncontrolled except when accessed directly from the Document Repositive Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red.		
DESCRIPTION:	WDFNW8 3.3x3.3, 0.65P (F	ull–Cut μ8FL WF)	PAGE 1 OF 1	

ON Semiconductor and are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. ON Semiconductor does not convey any license under its patent rights nor the rights of others.

onsemi, Onsemi, and other names, marks, and brands are registered and/or common law trademarks of Semiconductor Components Industries, LLC dba "onsemi" or its affiliates and/or subsidiaries in the United States and/or other countries. onsemi owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of onsemi's product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking.pdf. Onsemi reserves the right to make changes at any time to any products or information herein, without notice. The information herein is provided "as-is" and onsemi makes no warranty, representation or guarantee regarding the accuracy of the information, product features, availability, functionality, or suitability of its products for any particular purpose, nor does onsemi assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using onsemi products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by onsemi. "Typical" parameters which may be provided in onsemi data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. onsemi does not convey any license under any of its intellectual property rights nor the rights of others. onsemi products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA class 3 medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase

ADDITIONAL INFORMATION

TECHNICAL PUBLICATIONS:

 $\textbf{Technical Library:} \ \underline{www.onsemi.com/design/resources/technical-documentation}$

onsemi Website: www.onsemi.com

ONLINE SUPPORT: www.onsemi.com/support

For additional information, please contact your local Sales Representative at

www.onsemi.com/support/sales